


FORM PTO-1449	Atty. Docket No.: R11.12-0701	Appl. No.: 09/667,297
 <p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p>	First Named Inventor:	
	Eric R. Lovegren et al.	
	Filing Date	Group Art:
	September 22, 2000	2857

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
JRW	AA	3,665,466	5/23/72	Hibbard	343	12
JRW	AB	3,812,422	5/21/74	DeCarolus	324	58
JRW	AC	3,995,212	11/30/76	Ross	324	58.50
JRW	AD	4,161,731	7/17/79	Barr	343	14
JRW	AE	5,327,139	7/5/94	Johnson	342	22
JRW	AF	5,438,867	8/8/95	van der Pol	73	290
JRW	AG	5,500,649	3/19/96	Mowrey et al.	342	22
JRW	AH	5,599,449	2/4/97	Gnam et al.	210	495
JRW	AI	5,609,059	3/11/97	McEwan	73	290
JRW	AJ	5,610,611	3/11/97	McEwan	342	89
JRW	AK	5,661,251	8/26/97	Cummings et al.	73	866.5

## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translation Yes No
JRW	AL	EP 0 882 956 A2	12/9/98	EPO - Germany			X
JRW	AM	EP 0 882 957 A2	12/9/98	EPO - Germany			X
	AN						

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

JRW	AO	Matthias Weiß et al., 1997 IEEE MTT-S Digest, "NOVEL METHODS OF MEASURING IMPURITY LEVELS IN LIQUID TANKS," Publ. Date 6/8/97, pp. 1651-1654
JRW	AP	(SPECIAL REPORT) Flow, LEVEL, "Pressure, Radar level technology offers accurate, noncontact measurements," January 1996, I&CS, pp. 27-30
JRW	AQ	KROHNE Technical Data, BM100, BM100EEx, "Reflex-Radar," 12/96, 12 pages
EXAMINER: <i>John R. Woot</i>		DATE CONSIDERED: 02/28/02

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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JRW	AR	5,672,975	9/30/97	Kielb et al.	324	644
JRW	AS	5,835,053	11/10/98	Davis	342	22
JRW	AT	5,898,308	4/27/99	Champion	324	643
	AU					
	AV					
	AW					
	AX					
	AY					
	AZ					
	BA					

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FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
	BB					
	BC					
	BD					

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

JRW	BE	UCRL-ID-130474, J. Mast, et al., "Micropower Impulse Radar Technology and Applications," April 15, 1998, 14 pages
	BF	"FUNDAMENTALS OF APPLIED ELEDCTROMAGNETICS" 1999 Edition, Fawwaz T. Ulaby, PRENTICE HALL, Chapter 8, pp. 292-319
	BG	

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